



BYD Microelectronics Co., Ltd.

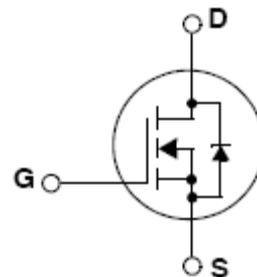
BF910N60/BF910N60L

600V N-Channel MOSFET

General Description

These N-Channel enhancement mode power field effect transistors are produced using DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, active power factor correction, electronic lamp ballasts based on half bridge topology.



Features

- $V_{DS} = 600\text{ V}$
- $I_D = 10\text{ A}$
- $R_{DS(ON)} = 0.65\ \Omega$ TYP ($V_{GS} = 10\text{ V}$, $I_D = 5.0\text{ A}$)
- Low C_{RSS} (typical 16pF)
- Fast switching



Absolute Maximum Ratings

Symbol	Parameter	BF910N60L	BF910N60	Unit
V_{DS}	Drain-Source Voltage	600		V
I_D	Drain Current(continuous)at $T_c = 25^\circ\text{C}$	10		A
I_{DM}	Drain Current (pulsed) (Note1)	40		A
V_{GS}	Gate-Source Voltage	± 30		V
E_{AS}	SinglePulseAvalanche Energy (Note2)	490		mJ
I_{AR}	Avalanche Current (Note1)	10		A
E_{AR}	RepetitiveAvalancheEnergy (Note1)	16		mJ
dv/dt	PeakDiodeRecovery dv/dt (Note3)	5.0		V/ns
P_D	Power Dissipation ($T_c = 25^\circ\text{C}$)	139	48	W
T_{stg}	Storage Temperature Range	-55 to $+150$		$^\circ\text{C}$
T_L	Maximum Lead Temperature for Soldering Purpose	300		$^\circ\text{C}$



Ordering Information

Part Number	Package	Packaging
BF910N60	TO-220F	Tube
BF910N60L	TO-220	Tube

Thermal Data

Symbol	Parameter	TO-220F	TO-220	Unit
Rthj-case	Thermal Resistance Junction-case	2.6	0.9	°C/W
Rthj-amb	Thermal Resistance Junction-ambient	62.5	62.5	°C/W

Electrical Characteristics($T_c = 25^\circ\text{C}$)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source Breakdown Voltage	$I_D=250\mu\text{A}$, $V_{GS}=0\text{V}$	600			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=600\text{V}$, $V_{GS}=0\text{V}$			1	μA
		$V_{DS}=600\text{V}$, $V_{GS}=0\text{V}$, $T_c=125^\circ\text{C}$			10	μA
I_{GSS}	Gate-body Leakage Current	$V_{GS}=\pm 30\text{V}$, $V_{DS}=0\text{V}$			± 100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$	2.0		4.0	V
$R_{DS(on)}$	Static Drain-source On Resistance	$V_{GS}=10\text{V}$, $I_D=5.0\text{A}$		0.65	0.73	Ω
C_{iss}	Input Capacitance	$V_{DS}=25\text{V}$, $f=1\text{MHz}$, $V_{GS}=0\text{V}$		1900		pF
C_{oss}	Output Capacitance			146		pF
C_{rss}	Reverse Transfer Capacitance			16		pF
$t_{d(on)}$	Turn-on Delay Time	$V_{DD}=300\text{V}$, $I_D=5\text{A}$ $V_{GS}=10\text{V}$, $R_G=4.7\Omega$ (Note4,5)		30		ns
t_r	Rise Time			18		ns
$t_{d(off)}$	Turn-off Delay Time			60		ns
t_f	Fall Time			24		ns
Q_g	Total Gate Charge	$V_{DD}=480\text{V}$, $I_D=10\text{A}$ $V_{GS}=10\text{V}$ (Note4,5)		55		nC
Q_{gs}	Gate-Source Charge			16		nC
Q_{gd}	Gate-Drain Charge			17.2		nC
$V_{SD(*)}$	Forward On Voltage	$I_F=10\text{A}$, $V_{GS}=0\text{V}$		0.81	1.2	V
T_{rr}	Reverse Recovery Time	$V_{DD}=300\text{V}$, $I_F=10\text{A}$, $di/dt=100\text{A}/\mu\text{s}$ (Note4)		450		ns

Notes:

1. Repetitive Rating : Pulse width limited by maximum junction temperature
 2. $L = 10\text{mH}$, $I_{AS} = 9.5\text{A}$, $V_{DD} = 50\text{V}$, $R_G = 25\Omega$, Starting $T_J = 25^\circ\text{C}$
 3. $I_{SD} \leq 10\text{A}$, $di/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$
 4. Pulse Test : Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$
 5. Essentially independent of operating temperature
- (*).Pulsed:Pulse duration

Typical characteristics (25°C unless noted)

Figure 1 Output Characteristics

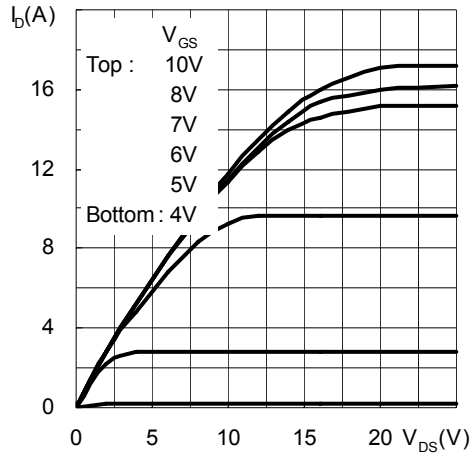


Figure 2 Transfer Characteristics

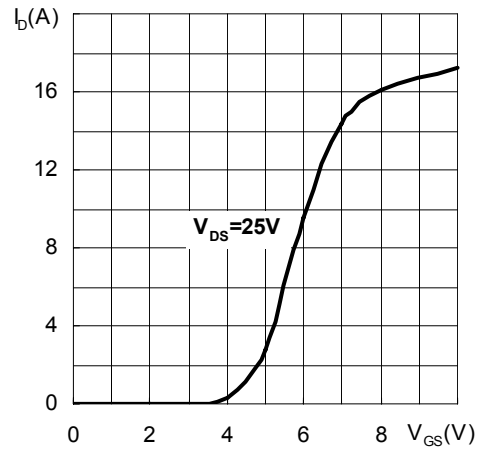


Figure 3 Normalized Threshold Voltage vs. Temperature

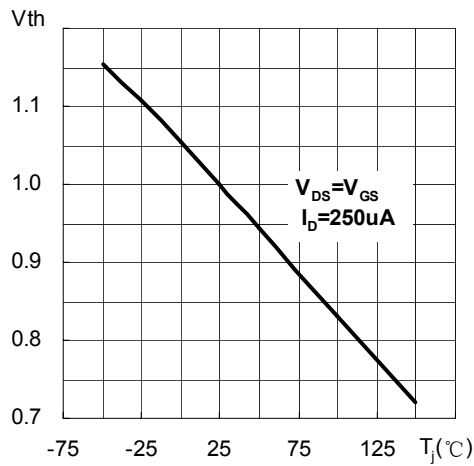


Figure 4 Normalized BV_{DSS} vs. Temperature

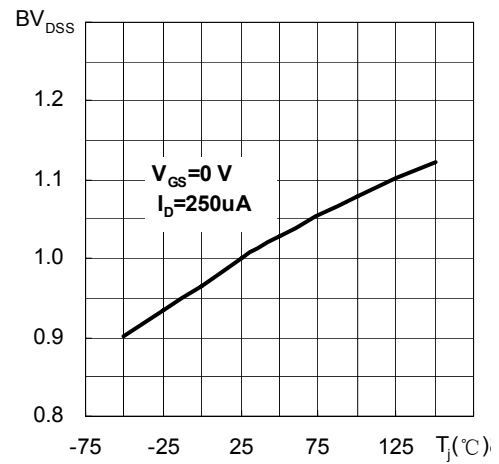


Figure 5 Normalized on Resistance vs Temperature

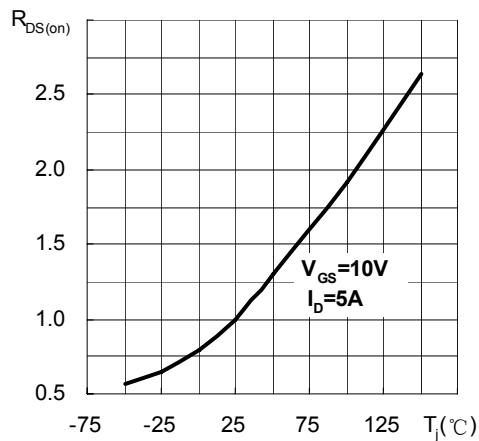


Figure 6 Source-Drain Diode Forward Characteristics

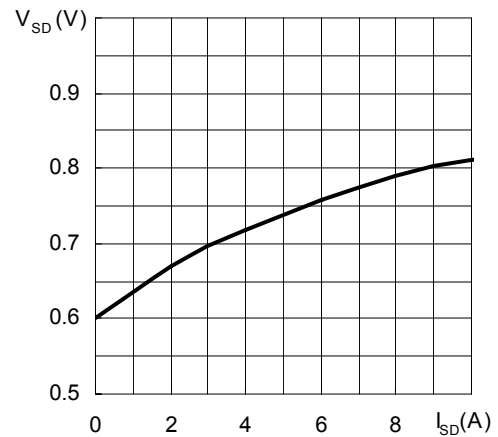


Figure 7 Capacitance

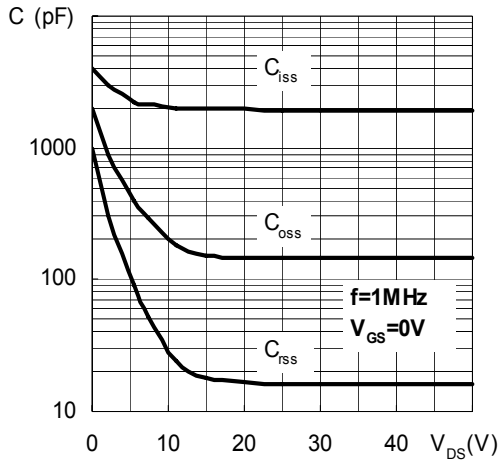


Figure 8 Gate Charge

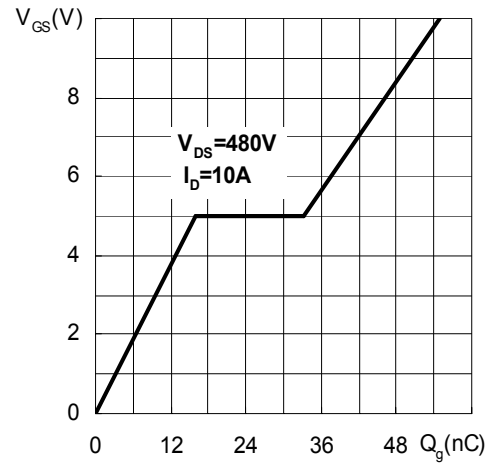


Figure 9-1 Maximum Safe Operating Area For BF910N60

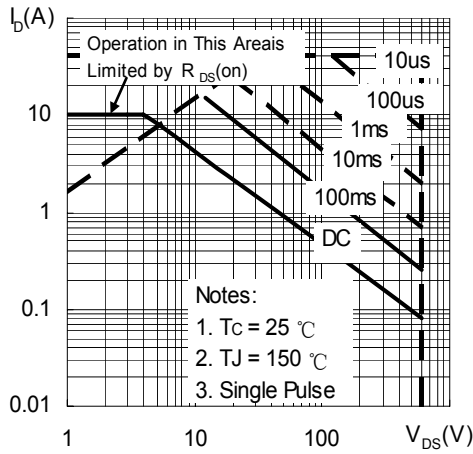


Figure 9-2 Maximum Safe Operating Area For BF910N60L

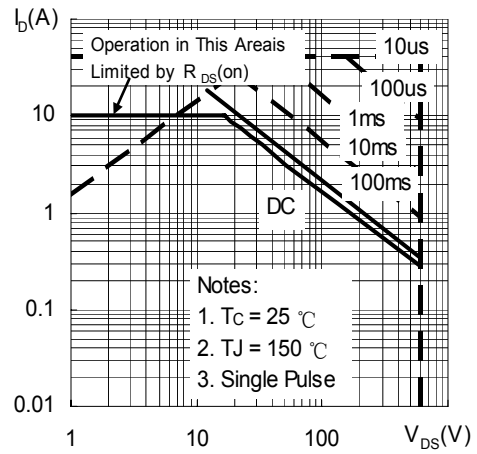


Figure 10 Maximum Drain Current vs Case Temperature

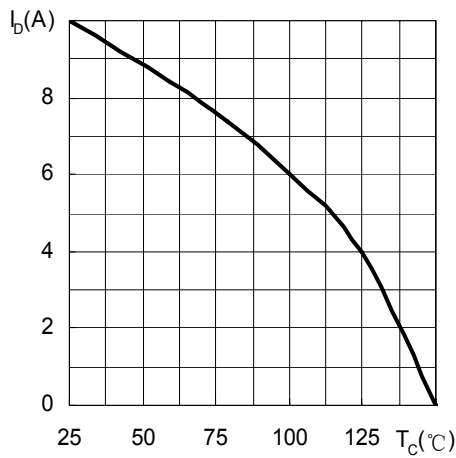


Figure 11-1 Maximum Transient Thermal Impedance For BF910N60

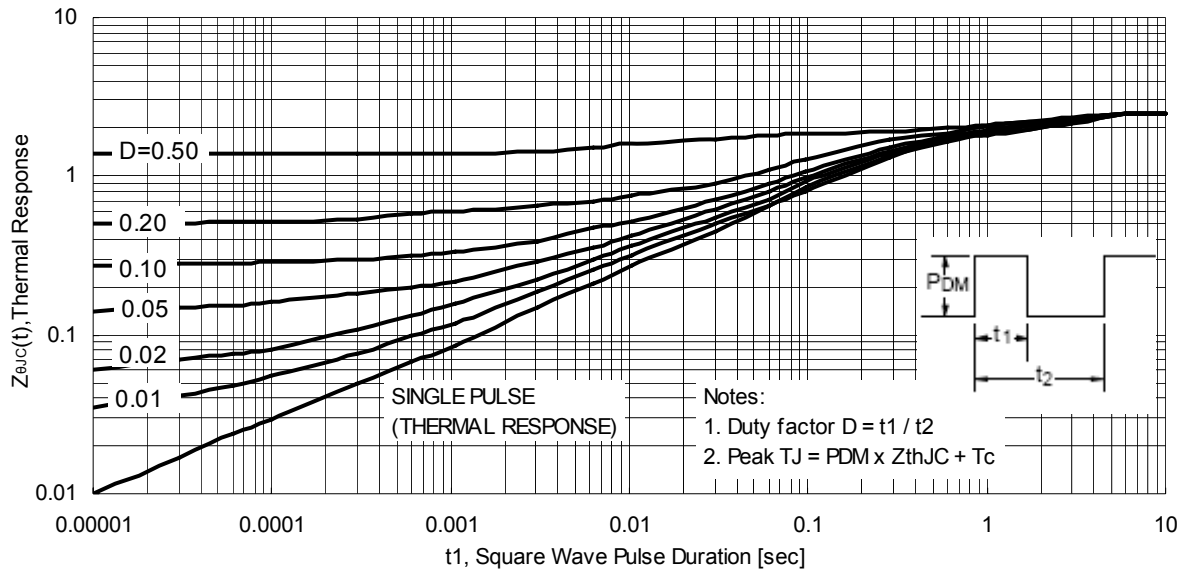
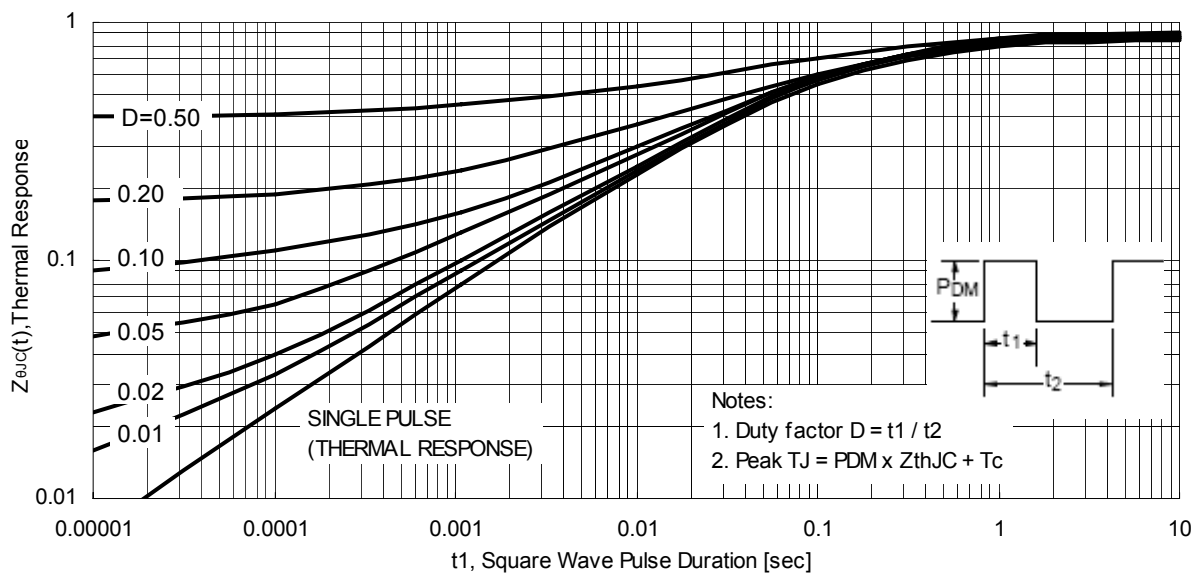
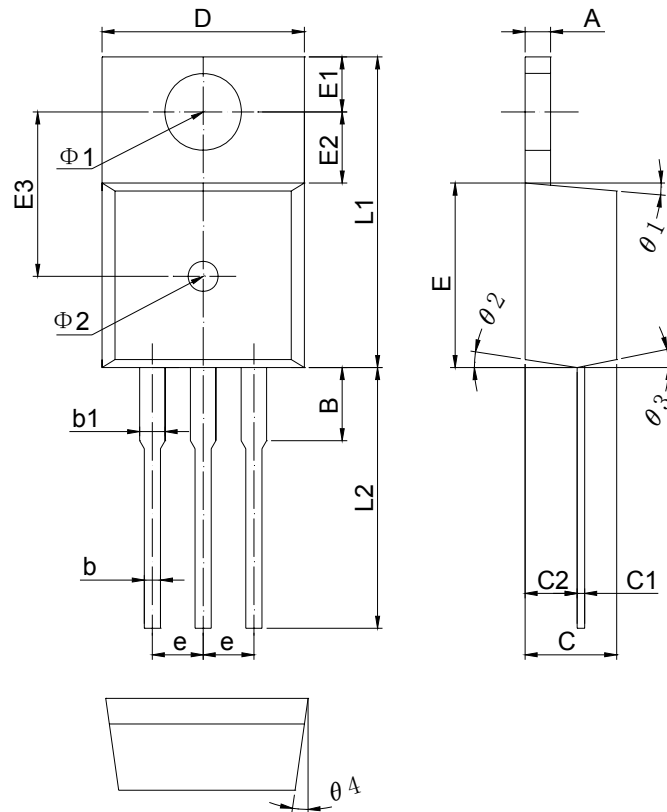


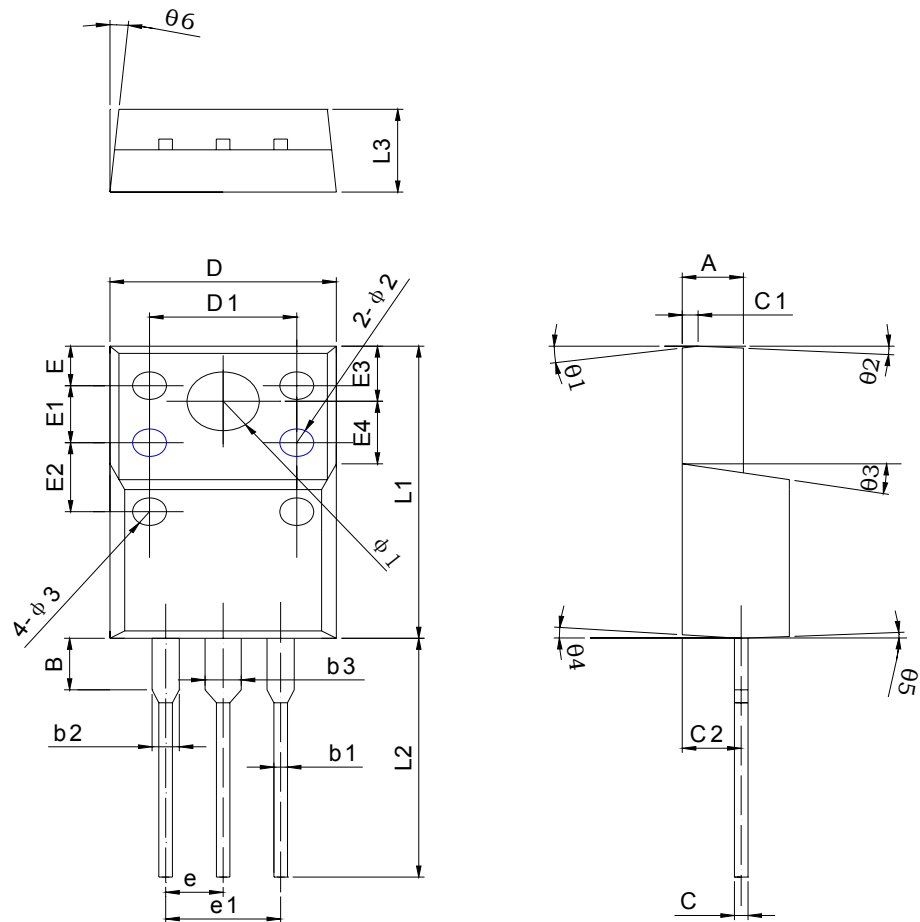
Figure 11-2 Maximum Transient Thermal Impedance For BF910N60L



**Package Drawing**
TO-220

Symbol	Dimensions In Millimeters			Dimensions In Inches		
	Min	Nom	Max	Min	Nom	Max
A	-	1.27	-	-	0.050	-
B	-	3.65	-	-	0.144	-
b	-	0.81	-	-	0.032	-
b1	-	1.27	-	-	0.050	-
C	-	4.58	-	-	0.180	-
C1	-	0.38	-	-	0.015	-
C2	-	2.60	-	-	0.102	-
D	10.10	10.12	10.14	0.398	0.398	0.399
E	-	9.20	-	-	0.362	-
E1	-	2.74	-	-	0.108	-
E2	-	3.55	-	-	0.140	-
E3	-	8.20	-	-	0.323	-
e	2.515	2.54	2.565	0.099	0.100	0.101
L1	15.47	15.49	15.51	0.609	0.610	0.611
L2	13.00	-	-	0.512	-	-
θ1	3°			3°		
θ2	3°			3°		
θ3	3°			3°		
θ4	3°			3°		
φ1	3.84			0.151		
φ2	1.5			0.059		

TO-220F





Symbol	Dimensions In Millimeters			Dimensions In Inches		
	Min	Nom	Max	Min	Nom	Max
A	2.50	2.70	2.90	0.098	0.106	0.114
B	2.60	2.80	3.00	0.102	0.110	0.118
b1	0.50	0.60	0.70	0.020	0.024	0.028
b2	1.10	1.20	1.30	0.043	0.047	0.051
b3	-	1.60	-	-	0.063	-
C	0.55	0.60	0.65	0.022	0.024	0.026
C1	-	0.60	-	-	0.024	-
C2	2.40	2.60	2.80	0.094	0.102	0.110
D	9.80	10.00	10.20	0.386	0.394	0.402
D1	-	6.50	-	-	0.256	-
E	-	2.15	-	-	0.085	-
E1	-	3.10	-	-	0.122	-
E2	-	3.75	-	-	0.148	-
E3	2.90	3.00	3.10	0.114	0.118	0.122
E4	3.30	3.40	3.50	0.130	0.134	0.138
e	-	2.54	-	-	0.100	-
e1	4.98	5.08	5.18	0.196	0.200	0.204
L1	14.80	15.00	15.20	0.583	0.591	0.598
L2	13.00	13.20	13.40	0.512	0.520	0.528
L3	4.30	4.50	4.70	0.169	0.177	0.185
Θ1	5°			5°		
Θ2	3°			3°		
Θ3	10°			10°		
Θ4	5°			5°		
Θ5	3°			3°		
Θ6	5°			5°		
φ1	3.00	3.20	3.40	0.118	0.126	0.134
φ2	1.50 深 1.2 头部 160°			1.50 深 1.2 头部 160°		
φ3	1.50 深 0.1			1.50 深 0.1		



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